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		APPLICANT MORIYA, et al.	
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

52	AU	TAKAGI, et al., "A New I-V Model for Stress-Induced Leakage Current Including Inelastic Tunneling", IEEE Transactions on Electron Devices, Vol. 46, No. 2, February 1999, pps. 348-354
52	AV	CAMPBELL, et al., "Titanium dioxide (TiO ₂)-based gate insulators", IBM J. Res. Develop. Vol. 43, No. 3, May 1999, pps. 383-392
	AW	
	AX	
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	AZ	
Examiner		Date Considered 9/27/02